

SEMiX151GAL12E4s



SEMiX® 1s

Trench IGBT Modules

SEMiX151GAL12E4s

Features

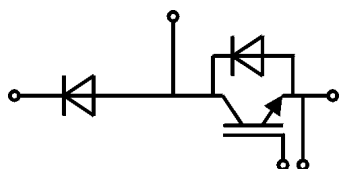
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability
- UL recognized, file no. E63532

Typical Applications*

- AC inverter drives
- UPS
- Electronic Welding

Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_J=150^\circ\text{C}$



GAL

Absolute Maximum Ratings

Symbol	Conditions	Values	Unit
IGBT			
V_{CES}	$T_J = 25^\circ\text{C}$	1200	V
I_C	$T_J = 175^\circ\text{C}$	$T_C = 25^\circ\text{C}$	232
		$T_C = 80^\circ\text{C}$	179
I_{Cnom}		150	A
I_{CRM}	$I_{CRM} = 3 \times I_{Cnom}$	450	A
V_{GES}		-20 ... 20	V
t_{psc}	$V_{CC} = 800\text{ V}$ $V_{GE} \leq 20\text{ V}$ $V_{CES} \leq 1200\text{ V}$	$T_J = 150^\circ\text{C}$	10
T_J		-40 ... 175	$^\circ\text{C}$
Inverse diode			
I_F	$T_J = 175^\circ\text{C}$	$T_C = 25^\circ\text{C}$	189
		$T_C = 80^\circ\text{C}$	141
I_{Fnom}		150	A
I_{FRM}	$I_{FRM} = 3 \times I_{Fnom}$	450	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_J = 25^\circ\text{C}$	900	A
T_J		-40 ... 175	$^\circ\text{C}$
Freewheeling diode			
I_F	$T_J = 175^\circ\text{C}$	$T_C = 25^\circ\text{C}$	189
		$T_C = 80^\circ\text{C}$	141
I_{Fnom}		150	A
I_{FRM}	$I_{FRM} = 3 \times I_{Fnom}$	450	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_J = 25^\circ\text{C}$	900	A
T_J		-40 ... 175	$^\circ\text{C}$
Module			
$I_{t(RMS)}$	$T_{terminal} = 80^\circ\text{C}$	600	A
T_{stg}		-40 ... 125	$^\circ\text{C}$
V_{isol}	AC sinus 50Hz, $t = 1\text{ min}$	4000	V

Characteristics

Symbol	Conditions	min.	typ.	max.	Unit
IGBT					
$V_{CE(sat)}$	$I_C = 150\text{ A}$ $V_{GE} = 15\text{ V}$ chipelevel	$T_J = 25^\circ\text{C}$	1.8	2.05	V
		$T_J = 150^\circ\text{C}$	2.2	2.4	V
V_{CE0}	chipelevel	$T_J = 25^\circ\text{C}$	0.8	0.9	V
		$T_J = 150^\circ\text{C}$	0.7	0.8	V
r_{CE}	$V_{GE} = 15\text{ V}$ chipelevel	$T_J = 25^\circ\text{C}$	6.7	7.7	$\text{m}\Omega$
		$T_J = 150^\circ\text{C}$	10.0	10.7	$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE}=V_{CE}, I_C = 6\text{ mA}$	5	5.8	6.5	V
I_{CES}	$V_{GE} = 0\text{ V}$ $V_{CE} = 1200\text{ V}$	$T_J = 25^\circ\text{C}$		2.0	mA
		$T_J = 150^\circ\text{C}$			mA
C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	9.3		nF
C_{oes}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	0.58		nF
C_{res}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	0.51		nF
Q_G	$V_{GE} = -8\text{ V...} + 15\text{ V}$		850		nC
R_{Gint}	$T_J = 25^\circ\text{C}$		5.00		Ω



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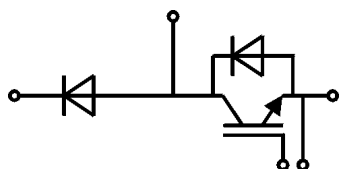
Typical Applications*

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Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_J=150^\circ\text{C}$

Characteristics					
Symbol	Conditions		min.	typ.	max. Unit
$t_{d(on)}$	$V_{CC} = 600\text{ V}$	$T_J = 150^\circ\text{C}$		204	ns
t_r	$I_C = 150\text{ A}$	$T_J = 150^\circ\text{C}$		42	ns
E_{on}	$V_{GE} = \pm 15\text{ V}$	$T_J = 150^\circ\text{C}$		16.6	mJ
$t_{d(off)}$	$R_{G\ on} = 1\ \Omega$	$T_J = 150^\circ\text{C}$		468	ns
t_f	$R_{G\ off} = 1\ \Omega$	$T_J = 150^\circ\text{C}$		91	ns
E_{off}	$di/dt_{on} = 3900\text{ A}/\mu\text{s}$	$T_J = 150^\circ\text{C}$		18.4	mJ
$R_{th(j-c)}$	$di/dt_{off} = 2000\text{ A}/\mu\text{s}$	$T_J = 150^\circ\text{C}$			
	per IGBT			0.19	K/W
Inverse diode					
$V_F = V_{EC}$	$I_F = 150\text{ A}$	$T_J = 25^\circ\text{C}$		2.1	2.46 V
	$V_{GE} = 0\text{ V}$	$T_J = 150^\circ\text{C}$		2.1	2.4 V
V_{F0}	chipelevel	$T_J = 25^\circ\text{C}$	1.1	1.3	1.5 V
		$T_J = 150^\circ\text{C}$	0.7	0.9	1.1 V
r_F	chipelevel	$T_J = 25^\circ\text{C}$	4.3	5.6	6.4 m Ω
		$T_J = 150^\circ\text{C}$	6.7	7.8	8.5 m Ω
I_{RRM}	$I_F = 150\text{ A}$	$T_J = 150^\circ\text{C}$		115	A
Q_{rr}	$di/dt_{off} = 3400\text{ A}/\mu\text{s}$	$T_J = 150^\circ\text{C}$		23	μC
E_{rr}	$V_{GE} = -15\text{ V}$	$T_J = 150^\circ\text{C}$		8.9	mJ
$R_{th(j-c)}$	$V_{CC} = 600\text{ V}$	$T_J = 150^\circ\text{C}$			
	per diode			0.31	K/W
Freewheeling diode					
$V_F = V_{EC}$	$I_F = 150\text{ A}$	$T_J = 25^\circ\text{C}$		2.1	2.46 V
	$V_{GE} = 0\text{ V}$	$T_J = 150^\circ\text{C}$		2.1	2.4 V
V_{F0}	chipelevel	$T_J = 25^\circ\text{C}$	1.1	1.3	1.5 V
		$T_J = 150^\circ\text{C}$	0.7	0.9	1.1 V
r_F	chipelevel	$T_J = 25^\circ\text{C}$	4.3	5.6	6.4 m Ω
		$T_J = 150^\circ\text{C}$	6.7	7.8	8.5 m Ω
I_{RRM}	$I_F = 150\text{ A}$	$T_J = 150^\circ\text{C}$		115	A
Q_{rr}	$di/dt_{off} = 3400\text{ A}/\mu\text{s}$	$T_J = 150^\circ\text{C}$		23	μC
E_{rr}	$V_{GE} = -15\text{ V}$	$T_J = 150^\circ\text{C}$		8.9	mJ
$R_{th(j-c)}$	$V_{CC} = 600\text{ V}$	$T_J = 150^\circ\text{C}$			
	per diode			0.31	K/W
Module					
L_{CE}				16	nH
$R_{CC'+EE'}$	res., terminal-chip	$T_C = 25^\circ\text{C}$		0.7	m Ω
		$T_C = 125^\circ\text{C}$		1	m Ω
$R_{th(c-s)}$	per module			0.075	K/W
M_s	to heat sink (M5)		3	5	Nm
M_t		to terminals (M6)	2.5	5	Nm
					Nm
w				145	g
Temperature Sensor					
R_{100}	$T_C=100^\circ\text{C}$ ($R_{25}=5\text{ k}\Omega$)			$493 \pm 5\%$	Ω
$B_{100/125}$	$R(T)=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$; $T[K]$;			$3550 \pm 2\%$	K



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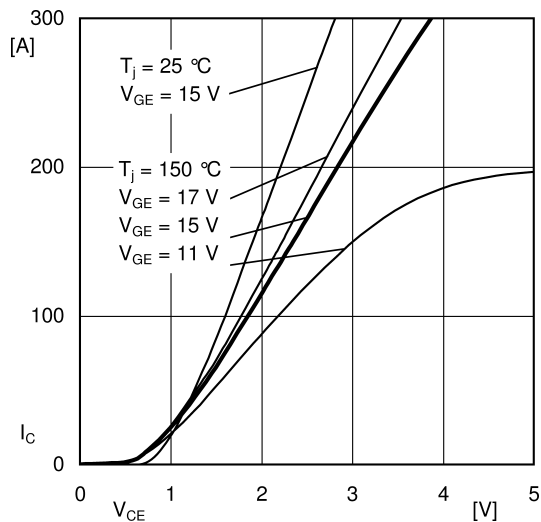


Fig. 1: Typ. output characteristic, inclusive $R_{CC'+EE'}$

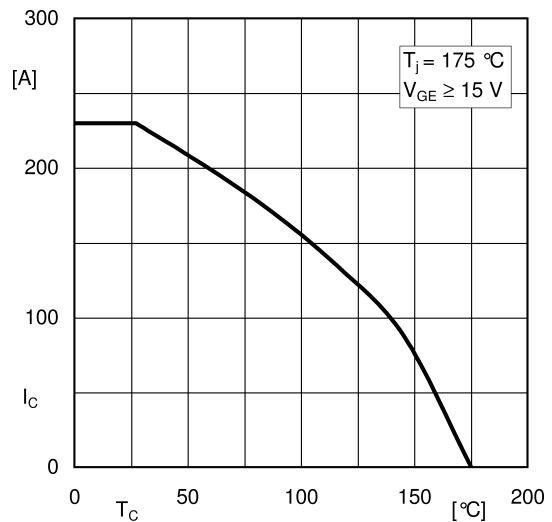


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

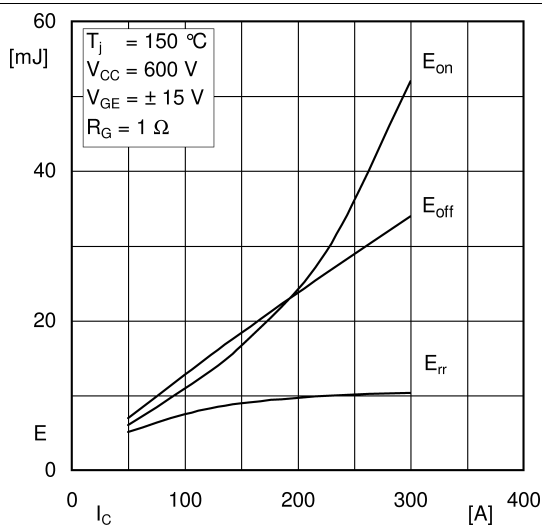


Fig. 3: Typ. turn-on /-off energy = $f(I_C)$

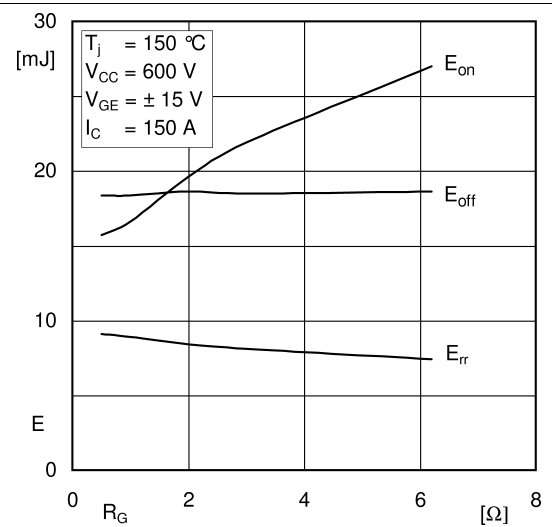


Fig. 4: Typ. turn-on /-off energy = $f(R_G)$

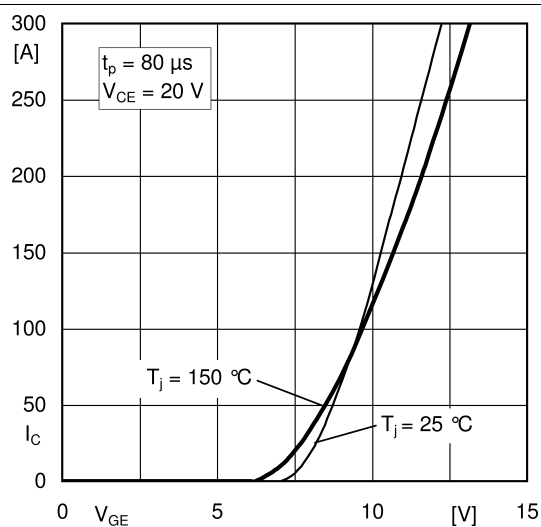


Fig. 5: Typ. transfer characteristic

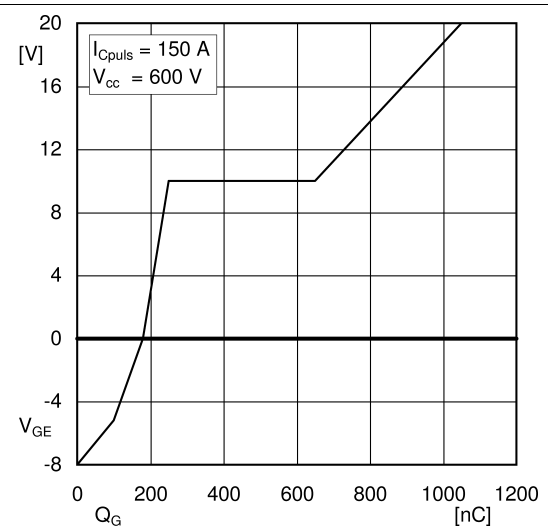
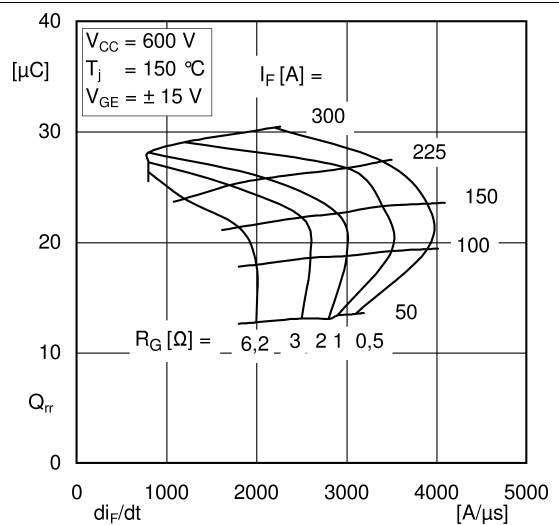
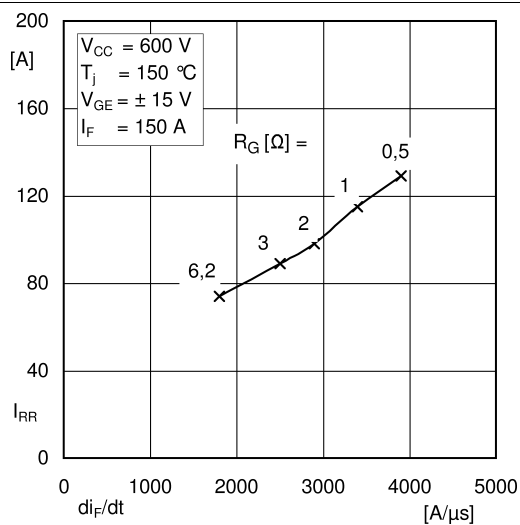
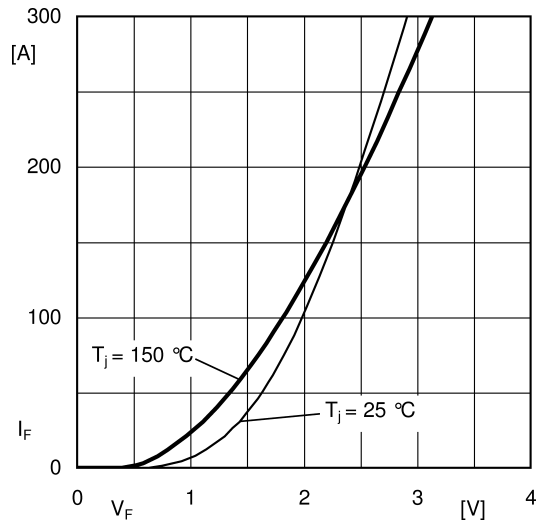
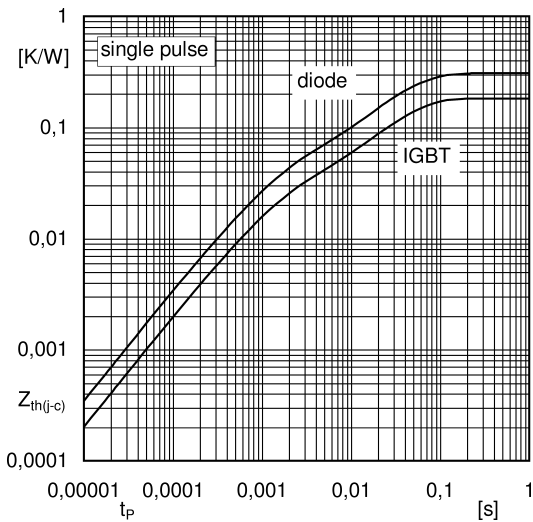
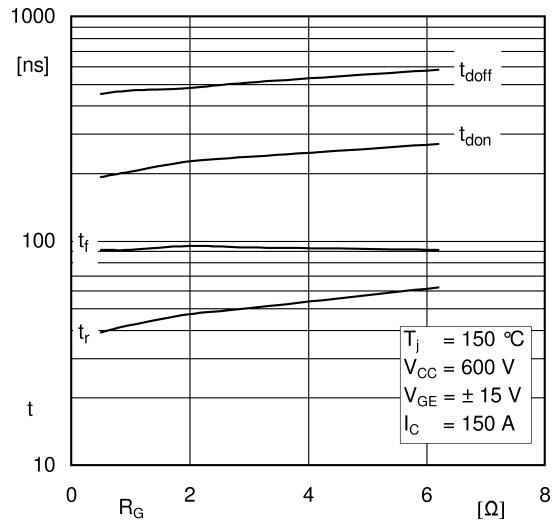
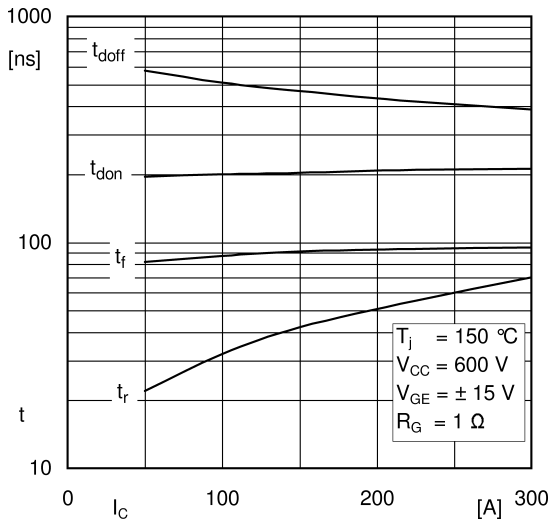
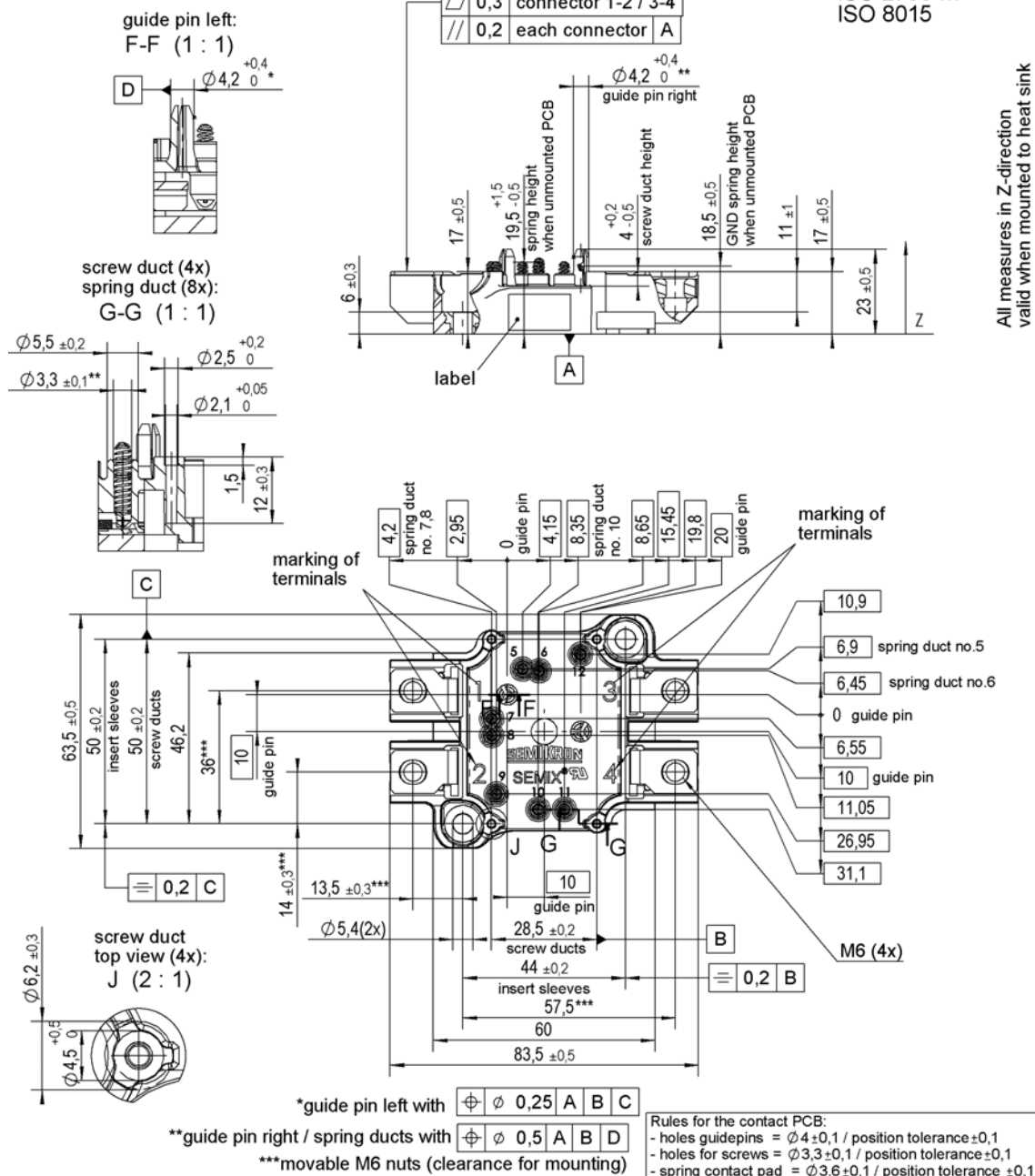


Fig. 6: Typ. gate charge characteristic

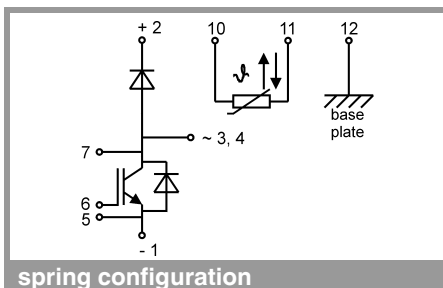


Case: SEMiX 1s

general tolerance:
ISO 2768-m
ISO 8015



SEMiX 1s



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX

* The specifications of our components may not be considered as an assurance of component characteristics. Components have to be tested for the respective application. Adjustments may be necessary. The use of SEMIKRON products in life support appliances and systems is subject to prior specification and written approval by SEMIKRON. We therefore strongly recommend prior consultation of our staff.